

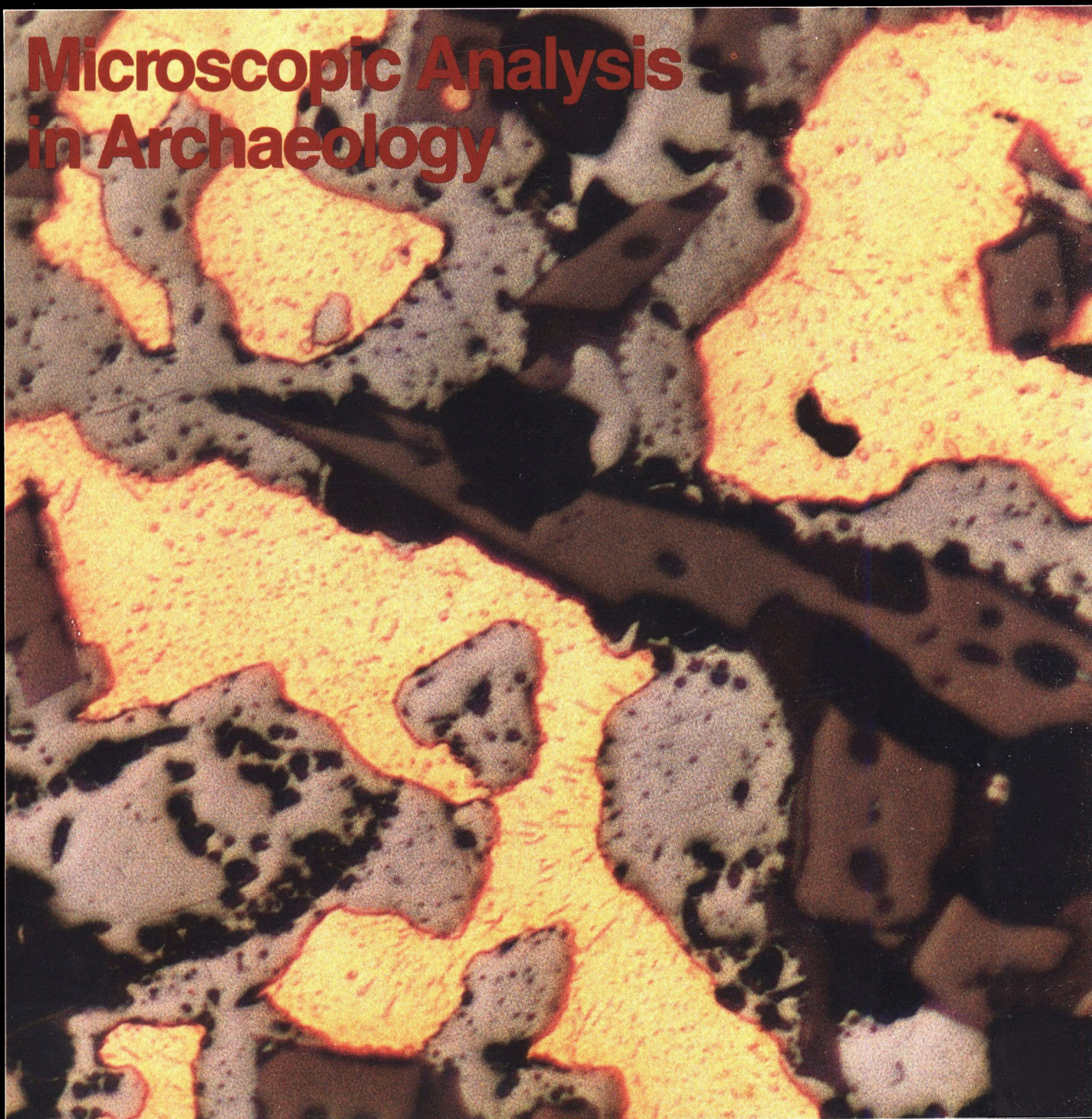
MRS BULLETIN

March 1989

Volume XIV, Number 3

Serving the International Materials Research Community

Microscopic Analysis in Archaeology





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ON THE COVER: Optical microstructure of a fragment of bronze-making slag from the pre-Roman Iron Age site at Roccagloriosa, southern Italy. Metallic copper, along with cuprite, is embedded in a glassy silicate matrix which also contains angular tin oxide particles and porosity. Magnification 320X. Microanalysis of prehistoric cultural materials is helping archaeologists decipher the complexities of our human past. For more on this theme, see the articles beginning on p. 21 in this issue.

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The Society's interdisciplinary approach to the exchange of technical information is qualitatively different from that provided by single-discipline professional societies because it promotes technical exchange across the various fields of science affecting materials development. MRS sponsors two major international annual meetings encompassing approximately 30 topical symposia, as well as numerous

single-topic scientific meetings each year. It recognizes professional and technical excellence, conducts short courses, and fosters technical exchange in various local geographic regions through Section activities and Student Chapters on university campuses.

MRS is an Affiliated Society of the American Institute of Physics and participates in the international arena of materials research through associations with professional organizations such as European MRS.

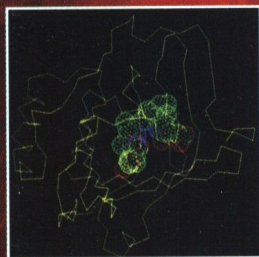
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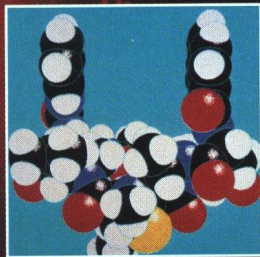
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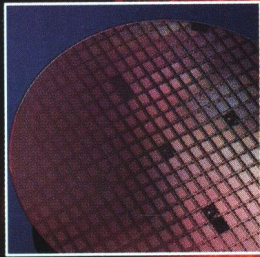
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